Homework 02

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Overview

1 Q1: Bias-variance tradeoff

2 Q2: Hastie and Tibshirani Summary

Bias Error

Also called 'Overfitting'

Variance

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Variance

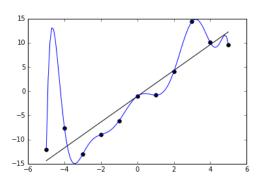
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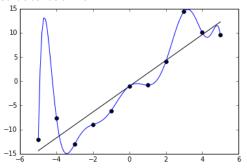


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- Predicts test data too well

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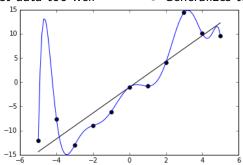


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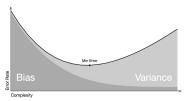
- Also called 'Underfitting'
- Generalizes too well



- Aiming for the lowest total error typically means finding a "middle-ground"
- A common technique for this is determining the minimum mean squared error.

$$MSE = \left(E\left[\hat{f}(x)\right] - f(x)\right)^{2} + E\left[\left(\hat{f}(x) - E\left[\hat{f}(x)\right]\right)^{2}\right] + \sigma_{e}^{2}$$

$$= Bias^{2} + Variance + Irreducible Error$$



Hastie Lectures Summary

- Statistical Learning and Regression
- Dimensionality and Parametric Models
- Assessing Model Accuracy and Bias-Variance Trade-Off
- Classification Problems and K-Nearest Neighbors

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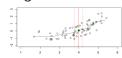
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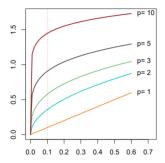
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 Structured models allowed allow flexible adjustment to obtain preferred level of fitting

Assessing Model Accuracy and Bias-Variance Trade-Off

• Mean-squared error is a good method for testing accuracy

$$\mathsf{MSE}_{\mathsf{Tr}} = \mathsf{AVE}_{i \in \mathsf{Tr}} \left[y_i - \hat{f}(x_i) \right]^2$$

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Assessing Model Accuracy and Bias-Variance Trade-Off

- Mean-squared error is a good method for testing accuracy
- But testing against training data will bias toward over-fit models
- Measuring against a separate batch of test data will likely provide a more accurate model

$$MSE_{Te} = AVE_{i \in Te} \left[y_i - \hat{f}(x_i) \right]^2$$

Classification Problems and K-Nearest Neighbors

- Goals of classification:
 - Build classifier model C(X)
 - Assess uncertainty of prediction
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 For any model the Baye's optimal classifier will be the result of combining conditional class probabilities:

$$C(x) = j$$
 if $p_j(x) = \max \{p_1(x), p_2(x), \dots, p_K(x)\}$